

# Solution-processable fullerene derivatives for organic photovoltaics and n-type thin-film transistors

Sun Young Nam<sup>a</sup>, Eun Young Park<sup>a</sup>, Tae-Dong Kim<sup>a,\*</sup>, Shinuk Cho<sup>b</sup>,  
Jea-Gun Park<sup>c</sup>, Kwang-Sup Lee<sup>a,\*</sup>

<sup>a</sup> Department of Advanced Materials, Hannam University, Daejeon 305-811, Republic of Korea

<sup>b</sup> Department of Physics, University of Ulsan, Ulsan 680-749, Republic of Korea

<sup>c</sup> Department of Electronics and Communications Engineering, Hanyang University, Seoul 133-791, Republic of Korea

## ARTICLE INFO

### Article history:

Received 4 October 2010

Accepted 29 November 2010

Available online 1 February 2011

### Keywords:

Organic photovoltaics

Organic thin-film transistors

Fullerene derivatives

Solution-processing

## ABSTRACT

Two solution-processable fullerene derivatives (C<sub>60</sub>TH-Hx and C<sub>60</sub>TH-Hx-a) were successfully synthesized for organic photovoltaics and n-type thin-film transistors. The best power conversion efficiency (PCE) was observed in a layered structure of P3HT:C<sub>60</sub>TH-Hx (PCE = 2.44%), which slightly exceeded that of P3HT:PCBM (PCE = 2.39%). We found a very low PCE for P3HT:C<sub>60</sub>TH-Hx-a (~0.14%) due to the poor solubility of C<sub>60</sub>TH-Hx-a. In addition, n-type thin-film transistors were fabricated by solution-processing techniques. The measured values of electron mobility in the devices for PCBM, C<sub>60</sub>TH-Hx, and C<sub>60</sub>TH-Hx-a were  $5.8 \times 10^{-3}$ ,  $2.5 \times 10^{-2}$ , and  $8.5 \times 10^{-4}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>, respectively.

© 2011 Elsevier B.V. All rights reserved.

## 1. Introduction

Recently there has been growing interest in organic photovoltaics (OPVs) because of their potential applications in low-cost, flexible, and extremely light-weight solar cells and photodetectors [1–5]. The common OPV configuration is a bulk heterojunction device, in which the active layer consists of a blend of electron-donating materials, for example, poly(3-hexylthiophene) (P3HT), and an electron-accepting material, such as [6,6]-phenyl C<sub>61</sub>-butyric acid methyl ester (PCBM). The power conversion efficiency (PCE) of the OPVs based on P3HT:PCBM reached over 4% by thermal treatment and solvent annealing under AM 1.5G illumination [6–8]. To further improve the PCE, new conjugated polymer donors and fullerene derivative acceptors are needed for a higher short-circuit current ( $I_{sc}$ ) and a higher open-circuit voltage ( $V_{oc}$ ). In recent years, significant efforts have been devoted to develop new low band-gap polymers and PCEs based on these polymers reached 5%–8% [9,10]. However attention has been much less focused on developing new fullerene derivatives in order to surpass or replace the PCBM molecule [11]. Li et al. have investigated the effect of alkyl chain length in the PCBM-like molecules on their photovoltaic properties [12]. Although there was little difference in the

absorption spectra and electronic energy level from the molecules, they found that the alkyl chain length exerted a significant influence on the photovoltaic performance. In our recent study, we have reported on a new fullerene derivative (C<sub>60</sub>TH-Hx) for n-type organic thin-film transistors (OTFTs) [13]. The devices showed an excellent n-channel performance with a highest mobility of  $2.8 \times 10^{-2}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>. The C<sub>60</sub>TH-Hx was prepared by a Prato reaction between C<sub>60</sub> and 3-hexylthiophene-2-carboxaldehyde with N-methylglycine, which gives better product yields and purities compared with a synthetic procedure for PCBM. This reaction provides a new pathway to explore molecular engineering of fullerene derivatives with facile synthetic routes.

Herein we designed and synthesized C<sub>60</sub>TH-Hx-a containing a hexyl group in different positions compared with C<sub>60</sub>TH-Hx. The photovoltaic performances for C<sub>60</sub>TH-Hx and C<sub>60</sub>TH-Hx-a in combination with P3HT were investigated. Furthermore, n-type OTFT devices of the molecules were fabricated by a solution-processing technique and compared with PCBM-based devices.

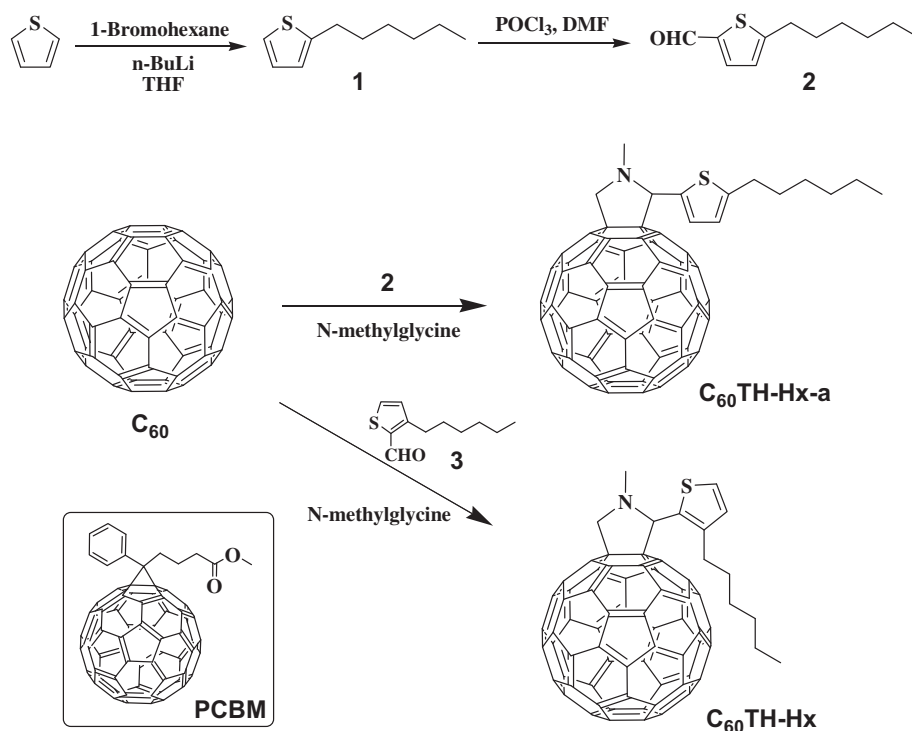
## 2. Experimental details

### 2.1. Chemicals

All reagents were purchased from commercial sources and used without further purification unless otherwise noted. All solvents were purified and freshly distilled prior to use according to

\* Corresponding authors. Tel.: +82 42 629 8857; fax: +82 42 629 8854.

E-mail addresses: [tdkim@hnu.kr](mailto:tdkim@hnu.kr) (T.-D. Kim), [kslee@hnu.kr](mailto:kslee@hnu.kr) (K.-S. Lee).



**Scheme 1.** The molecular structures and synthetic routes for  $C_{60}$ TH-Hx and  $C_{60}$ TH-Hx-a.

literature procedures. The synthetic procedure of  $C_{60}$ TH-Hx was previously reported in the literature [13].

### 2.1.1. Synthesis of 2-hexylthiophene (1)

A solution containing thiophene (0.10 mol) in dry THF (120 mL) at  $-78^{\circ}\text{C}$  was treated with 1.6 M of *n*-BuLi (0.12 mol) in hexane and stirred for 1 h. 1-bromohexane (0.12 mol) in dry THF (20 mL) was slowly added to the solution at  $-78^{\circ}\text{C}$  and the solution was allowed to warm to RT and stirred overnight. The solution was quenched with a saturated  $\text{NH}_4\text{Cl}$  solution and extracted with ether. The combined ether extracts were washed with brine, dried over  $\text{MgSO}_4$ , filtered, and concentrated under a reduced pressure. The resulting crude product was purified by flash chromatography on silica gel with an eluent of hexane to yield compound **1** (yield: 80%).  $^1\text{H}$  NMR ( $\text{CDCl}_3$ , TMS, ppm):  $\delta$  7.07 (d, 1H), 6.86 (t, 1H), 6.73 (d, 1H), 2.81 (t, 2H), 1.69 (m, 2H), 1.30 (m, 6H), 0.83 (t, 3H).

### 2.1.2. Synthesis of 5-hexylthiophene-2-carbaldehyde (2)

A solution of DMF (0.10 mol) and dry  $\text{CH}_2\text{Cl}_2$  (20 mL) at  $0^{\circ}\text{C}$ ,  $\text{POCl}_3$  (0.10 mol) was slowly added. The mixture was warmed to around  $40^{\circ}\text{C}$  until a clear pale yellow solution was obtained. The prepared solution was added into a solution of compound **1** (0.08 mol) in dry  $\text{CH}_2\text{Cl}_2$  (50 mL) at  $0^{\circ}\text{C}$ . After standing for 12 h at room temperature (RT), aqueous 1 M NaOH was added to the solution for neutralization. Filtration, washing with water, and drying gave light yellow oil. The resulting crude product was

purified by flash chromatography on silica gel with an eluent of hexane/ $\text{CH}_2\text{Cl}_2$  (1:1) to yield compound **2** (yield: 70%).  $^1\text{H}$  NMR ( $\text{CDCl}_3$ , TMS, ppm):  $\delta$  9.74 (s, 1H), 7.53 (d, 1H), 6.83 (d, 1H), 2.80 (m, 2H), 1.64 (m, 2H), 1.26 (m, 6H), 0.82 (t, 3H).

### 2.1.3. Synthesis of $C_{60}$ TH-Hx-a

A solution of **2** (0.09 mol), fullerene (0.09 mol), and *N*-methylglycine (0.20 mol) in 1,2-dichlorobenzene (30 mL) was refluxed for 48 h. After cooling to RT, the reaction mixture was performed with flash chromatography on silica gel with a gradient eluent of toluene to 20% hexane in toluene. After the crude product was washed and centrifuged with ethanol, recrystallization from 1,4-dioxane yielded the desired product of  $C_{60}$ TH-Hx-a (yield: 35%).  $^1\text{H}$  NMR ( $\text{CDCl}_3$ , TMS, ppm):  $\delta$  7.18 (d, 1H), 6.65 (d, 1H), 5.18 (s, 1H), 4.98 (d, 1H), 4.21 (d, 1H), 2.89 (s, 3H), 2.80 (t, 2H), 1.62 (m, 2H), 1.22 (m, 6H), 0.83 (t, 3H). MALDI-TOF-MS (matrix, 2-(4-hydroxyphenylazo)benzoic acid (HABA)): calcd for  $\text{C}_{67}\text{H}_9\text{NS}$  943.14; found 942.28 [ $\text{M}^+$ ], m.p.  $280^{\circ}\text{C}$ .

## 2.2. Characterization

$^1\text{H}$  NMR spectra (300 MHz) were taken on a Varian 300 spectrometer and mass spectra were recorded on a JMS-AX505WA mass spectrometer. Differential scanning calorimetry (DSC) was performed on a TA instruments Q50 at a ramping rate of  $10^{\circ}\text{C}/\text{min}$  under a nitrogen atmosphere. Atomic force microscopy (AFM) was performed using a Digital Instruments Nanoscope IV operated in tapping mode ( $\sim 350$  kHz frequency, Si tip).

## 2.3. Photovoltaic device fabrication and measurement

Bulkheterojunction photovoltaic devices were fabricated on an indium tin oxide (ITO) coated glass substrate. Poly(3,4-ethylenedioxythiophene):poly(styrenesulfonate) (PEDOT:PSS) was spin-coated in air at 5000 rpm for 40 s onto the ITO/glass. The

**Table 1**  
Solubility of PCBM,  $C_{60}$ TH-Hx, and  $C_{60}$ TH-Hx-a in various solvents.

Materials	Measured solubility (mg/mL)		
	Toluene	Chlorobenzene	Chloroform
PCBM	22	26	13
$C_{60}$ TH-Hx	10	15	<1
$C_{60}$ TH-Hx-a	<1	4	<1

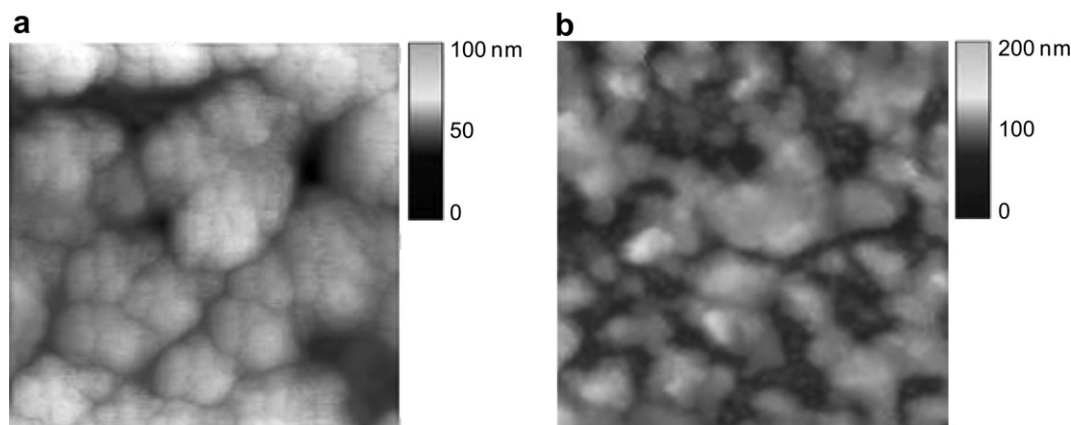


Fig. 1. AFM topographic height images ( $3\ \mu\text{m} \times 3\ \mu\text{m}$ ) of (a)  $\text{C}_{60}\text{TH-Hx}$  and (b)  $\text{C}_{60}\text{TH-Hx-a}$  films spin-coated on HMDS-treated  $\text{SiO}_2$  substrates.

substrate was subsequently dried for 10 min at  $140\ ^\circ\text{C}$ . The blend solutions of P3HT:fullerene derivative (1:1 weight ratio) in 1,2-dichlorobenzene were spin-coated onto the PEDOT:PSS/ITO/glass.  $\text{TiO}_x$  solution (diluted by 1:200 in methanol) was then spin-coated on top of the film (5000 rpm for 40 s) to perform as a symmetry-breaking and electron extraction layer. The devices were heated at  $80\ ^\circ\text{C}$  for 10 min. Finally, Al metal was deposited by thermal evaporation in a high vacuum ( $4 \times 10^{-6}$  mbar). Current–Voltage characteristic curves were measured using a Keithley 2400 source meter. Photovoltaic property was measured using an AM 1.5G illumination ( $100\ \text{mW}/\text{cm}^2$ ). All devices were encapsulated with UV epoxy and a cover glass (inside a glove box filled with  $\text{N}_2$ ).

#### 2.4. OTFT fabrication and measurement

1.0 wt% of active organic semiconductors in 1,2-dichlorobenzene were spin-coated onto the  $\text{SiO}_2$  substrates treated with hexamethyldisilazane (HMDS). A film thickness of 30–50 nm was obtained at a spin rate of 2000 rpm for 60 s. Bilayer top-contact electrodes consisting of Mg/Al (10 nm/120 nm) were evaporated under high vacuum ( $10^{-6}$  mbar) through a shadow mask. All the OTFT devices were encapsulated by a glass can and getters in an inert argon environment inside a glove box system. Electrical measurements were performed at RT under an argon atmosphere using an HP4156C semiconductor parameter analyzer.

### 3. Results and discussion

The synthetic approach for  $\text{C}_{60}\text{TH-Hx}$  and  $\text{C}_{60}\text{TH-Hx-a}$  is depicted in Scheme 1. The hexyl group was introduced to the 2- and 3-position in thiophene to afford 2-hexylthiophene and 3-hexylthiophene, respectively. 5-hexylthiophene-2-carbaldehyde (compound **2**) and 3-hexylthiophene-2-carbaldehyde (compound **3**) were synthesized by the Vilsmeier reaction.  $\text{C}_{60}\text{TH-Hx-a}$  (or  $\text{C}_{60}\text{TH-Hx}$ ) was obtained by the Prato reaction between fullerene and compound **2** (or **3**) with N-methylglycine refluxing in 1,2-dichlorobenzene for 48 h. The thermal property of  $\text{C}_{60}\text{TH-Hx-a}$  and  $\text{C}_{60}\text{TH-Hx}$  was evaluated by differential scanning calorimetry (DSC) in a nitrogen atmosphere at a rate of heating of  $10\ ^\circ\text{C}/\text{min}$ . Upon heating, one endothermic peak at  $280\ ^\circ\text{C}$  and  $220\ ^\circ\text{C}$  corresponding to the crystalline-to-isotropic phase transition was observed for  $\text{C}_{60}\text{TH-Hx-a}$  and  $\text{C}_{60}\text{TH-Hx}$ , respectively.

Table 1 shows quantitative solubility of  $\text{C}_{60}\text{TH-Hx-a}$ ,  $\text{C}_{60}\text{TH-Hx}$ , and PCBM in various solvents at  $25\ ^\circ\text{C}$ .  $\text{C}_{60}\text{TH-Hx}$  and PCBM were readily soluble in aromatic solvents, such as chlorobenzene, while  $\text{C}_{60}\text{TH-Hx-a}$  dissolved poorly in such solvents.  $\text{C}_{60}\text{TH-Hx-a}$  has an alkyl chain on the thiophene with a different position compared to  $\text{C}_{60}\text{TH-Hx}$ . The alkyl chain of  $\text{C}_{60}\text{TH-Hx-a}$  can extend outwards from the fullerene unit resulting in high crystallinity and poor solubility.

Structural characterization of spin-coated  $\text{C}_{60}\text{TH-Hx-a}$  and  $\text{C}_{60}\text{TH-Hx}$  on HMDS-treated  $\text{SiO}_2/\text{Si}$  substrates was performed by AFM. Fig. 1 shows topography images ( $3 \times 3\ \mu\text{m}$ ) of both films.

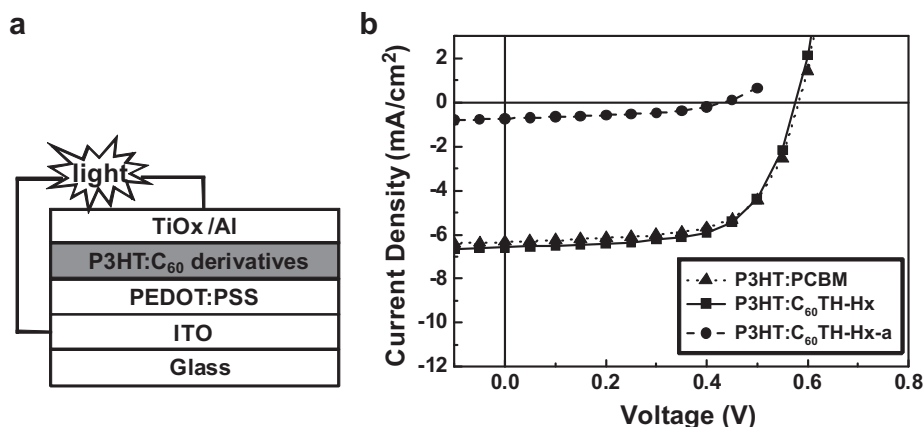


Fig. 2. (a) A schematic of OPV device architecture and (b) current–voltage ( $I$ – $V$ ) characteristics of OPV devices for P3HT:PCBM (triangle), P3HT: $\text{C}_{60}\text{TH-Hx}$  (square), and P3HT: $\text{C}_{60}\text{TH-Hx-a}$  (circle) under AM 1.5G illumination.

**Table 2**

Photovoltaic performance of the devices based on the blend of P3HT with PCBM, C<sub>60</sub>TH-Hx, and C<sub>60</sub>TH-Hx-a (1:1 w/w) under AM 1.5G illumination.

Materials	$I_{sc}$ (mA/cm <sup>2</sup> )	$V_{oc}$ (V)	FF	PCE (%)
P3HT:PCBM	6.32	0.58	0.65	2.39
P3HT:C <sub>60</sub> TH-Hx	6.58	0.58	0.64	2.44
P3HT:C <sub>60</sub> TH-Hx-a	0.73	0.43	0.44	0.14

Densely packed grains with average diameters of about 200–600 nm were observed throughout the image in the C<sub>60</sub>TH-Hx film. The more irregular grain sizes and less uniform surface were exhibited in C<sub>60</sub>TH-Hx-a, indicating a pronounced tendency of crystallite aggregation for C<sub>60</sub>TH-Hx-a. The microstructures of C<sub>60</sub>TH-Hx-a and C<sub>60</sub>TH-Hx will be further investigated by X-ray diffraction (XRD) measurements.

Bulkheterojunction photovoltaic devices with a 100 nm thick composite film (weight ratio of P3HT:fullerene derivatives = 1:1) as the active layer were fabricated by spin-coating from chlorobenzene solution on the top of a pre-patterned ITO substrate covered by 100 nm of PEDOT:PSS. In the case of the device with a TiO<sub>x</sub> layer, the TiO<sub>x</sub> precursor solution was applied in air on the top of the P3HT:fullerene derivative composition. It serves as an optical spacer to increase the PCE by creating more photogenerated charge carriers in the bulkheterojunction layer [14]. Subsequently a thin layer of aluminum was thermally deposited under a vacuum (Fig. 2(a)).

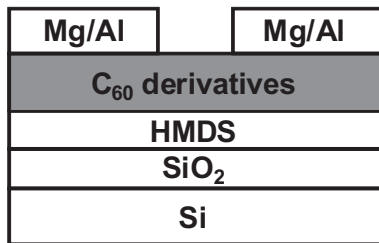
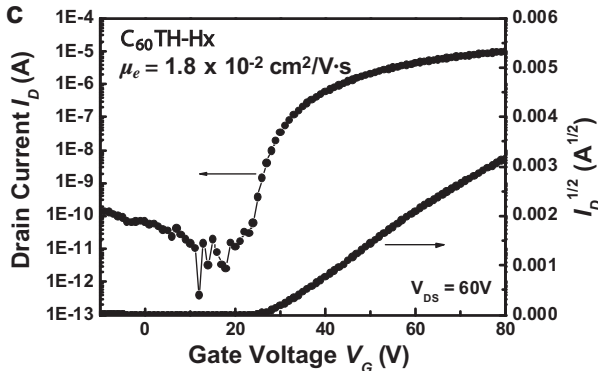
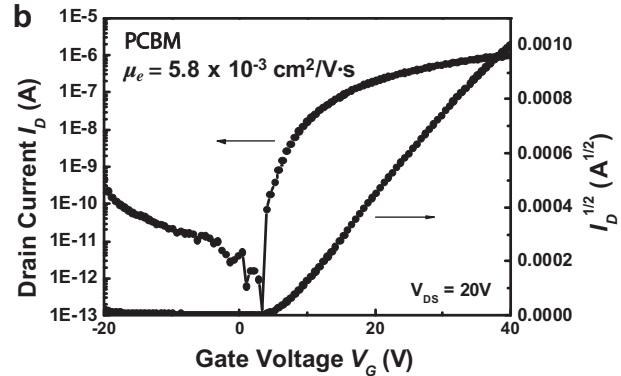
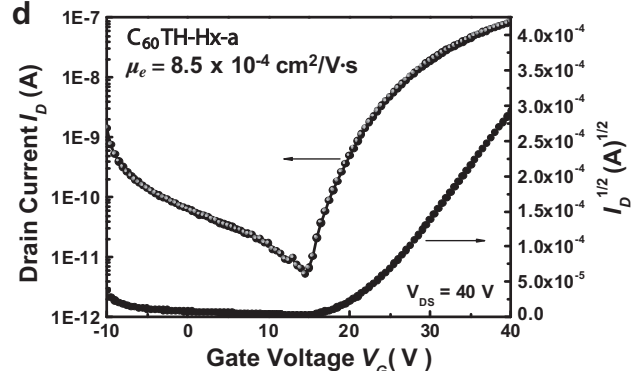
The photovoltaic characteristics were measured under an AM 1.5G solar simulator. The power conversion efficiency, PCE, and fill factor, FF, were calculated by the following equations:

$$PCE = FF \times I_{sc} \times V_{oc} / P_{in} \quad (1)$$

$$FF = I_m V_m / I_{sc} V_{oc} \quad (2)$$

where  $P_{in}$  is the incident radiation flux,  $I_{sc}$  and  $V_{oc}$  are the short-circuit current density and open-circuit voltage, respectively, and  $I_m$  and  $V_m$  are the current and voltage for maximum power output, respectively. The optimized device performances are summarized in Table 2. The current–voltage curves of the devices based on the three blending systems, P3HT:PCBM, P3HT:C<sub>60</sub>TH-Hx, and P3HT:C<sub>60</sub>TH-Hx-a, are shown in Fig. 2(b). The P3HT:PCBM device serves as a reference for the comparison of the efficiencies of the newly synthesized fullerene derivatives. The best performance is observed in the P3HT:C<sub>60</sub>TH-Hx, which exhibits the PCE of 2.44% with  $I_{sc} = 6.58$  mA/cm<sup>2</sup>,  $V_{oc} = 0.43$  V, and FF = 0.64. These values are slightly higher than those of the P3HT:PCBM device (PCE = 2.39%). Since the electronic states of the C<sub>60</sub> portions in C<sub>60</sub>TH-Hx and PCBM are expected to be similar due to the linkers added to a 6:6 ring juncture of C<sub>60</sub> [15], they hardly influenced the photovoltaic properties for both devices. However, in the case of P3HT:C<sub>60</sub>TH-Hx-a, the PCE significantly decreased to 0.14%. As mentioned earlier, C<sub>60</sub>TH-Hx-a has poorer solubility than C<sub>60</sub>TH-Hx due to the alkyl chain extended outwards from the fullerene unit, which resulted in irregular grain sizes and inhomogeneous surface in the film. Therefore, the poorer PCE of the P3HT:C<sub>60</sub>TH-Hx-a device may be due to the morphology and interface of the films. Similar behavior appeared on the OTFT performance for PCBM, C<sub>60</sub>TH-Hx, and C<sub>60</sub>TH-Hx-a.

To explore the electron transport properties of PCBM, C<sub>60</sub>TH-Hx, and C<sub>60</sub>TH-Hx-a, n-type transistors were fabricated on HMDS-treated SiO<sub>2</sub> substrates by spin-coating from 1,2-dichlorobenzene solution under ambient conditions. Mg/Al source and drain electrodes were deposited on the films by using thermal evaporation under a high vacuum. The channel length ( $L$ ) and width ( $W$ ) of the transistors were 50  $\mu$ m and 3 mm, respectively. The OTFT device geometry is shown in Fig. 3(a). The electron transfer characteristics were compared in Fig. 3(b)–(d) for PCBM with a drain voltage ( $V_D$ )

**a****c****b****d**

**Fig. 3.** (a) A schematic of OTFT device architecture and transfer characteristics of the drain current versus gate voltage ( $I_D$ – $V_G$ ) and the square root of drain current–gate voltage ( $I_D^{1/2}$ – $V_G$ ) for (b) PCBM, (c) C<sub>60</sub>TH-Hx, and (d) C<sub>60</sub>TH-Hx-a device.

**Table 3**

OTFT performance of spin-coated PCBM, C<sub>60</sub>TH-Hx, and C<sub>60</sub>TH-Hx-a devices on HMDS-treated SiO<sub>2</sub> substrates.

Materials	Spin speed (rpm)	Mobility (cm <sup>2</sup> /V s)	<i>I</i> <sub>on</sub> / <i>I</i> <sub>off</sub> ratio	Threshold volt (V)
PCBM	2000	$5.8 \times 10^{-3}$	$\sim 1 \times 10^4$	18
C <sub>60</sub> TH-Hx	2000	$1.8 \times 10^{-2}$	$\sim 1 \times 10^5$	14
C <sub>60</sub> TH-Hx-a	1000	$8.5 \times 10^{-4}$	$\sim 1 \times 10^5$	21

of 20 V, C<sub>60</sub>TH-Hx with a *V*<sub>D</sub> of 60 V, and C<sub>60</sub>TH-Hx-a with a *V*<sub>D</sub> of 40 V, respectively. All devices exhibited excellent n-type transistor characteristics. The electron mobility ( $\mu_e$ ) and the threshold voltage (*V*<sub>T</sub>) were estimated from the square root of drain current – gate voltage (*I*<sub>D</sub><sup>1/2</sup> – *V*<sub>G</sub>) plots, according to the standard equation in the saturation regime,  $I_D = (W/2L)\mu_e C_i (V_G - V_T)$ , where *I*<sub>D</sub> is the drain current, *W* and *L* are the conduction channel width and length, respectively, *C*<sub>i</sub> is the capacitance per unit area of gate dielectric, and *V*<sub>G</sub> is the gate voltage. The electron mobilities were in the range of  $\mu_e = 5.8 \times 10^{-3}$  cm<sup>2</sup>/V s for PCBM,  $1.8 \times 10^{-2}$  cm<sup>2</sup>/V s for C<sub>60</sub>TH-Hx, and  $8.5 \times 10^{-4}$  cm<sup>2</sup>/V s for C<sub>60</sub>TH-Hx-a. In Table 3, OTFT properties of each device are summarized. Among the OTFT devices, the lowest mobility value was observed in the C<sub>60</sub>TH-Hx-a, which exhibited the poorest photovoltaic performance. The C<sub>60</sub>TH-Hx device exhibited the best performance with a highest mobility of  $1.8 \times 10^{-2}$  cm<sup>2</sup>/V s with the on/off current ratio (*I*<sub>on</sub>/*I*<sub>off</sub>) of  $\sim 1.0 \times 10^5$  and a *V*<sub>T</sub> of 14 V. Interestingly, we could utilize an ink-jet-printing method for C<sub>60</sub>TH-Hx in order to fabricate OTFT devices exhibiting higher mobility ( $2.8 \times 10^{-2}$  cm<sup>2</sup>/V s) and a lower *V*<sub>T</sub> (7 V) than the spin-coated device [13]. This indicates that suitable modification of the fullerene can provide an opportunity to find alternatives of PCBM without deterioration of its photovoltaic and OTFT performances.

#### 4. Conclusion

We have synthesized fullerene derivatives, C<sub>60</sub>TH-Hx and C<sub>60</sub>TH-Hx-a, and compared with PCBM with regards to the characterization of photovoltaics and OTFTs. The thin-film devices were

fabricated by solution-processable techniques, such as spin-coating. The C<sub>60</sub>TH-Hx blended with P3HT (1:1) exhibited best photovoltaic performance (PCE = 2.44%) compared with PCBM and C<sub>60</sub>TH-Hx-a. In addition, the C<sub>60</sub>TH-Hx showed excellent OTFT characteristics, which possessed a highest mobility of  $1.8 \times 10^{-2}$  cm<sup>2</sup>/V s with an *I*<sub>on</sub>/*I*<sub>off</sub> of  $\sim 1.0 \times 10^5$  and a *V*<sub>T</sub> of 14 V.

#### Acknowledgements

This study was supported by the National Research Program for Terabit Nonvolatile Memory Development and the Fundamental R&D Program for Core Technology of Materials (M2007010004) funded by the Ministry of Knowledge Economy and also by the Mid-career Researcher Program through NRF grant funded by the MEST (No. 2010-0000499). T.-D. Kim acknowledges supports from Korea National Research Foundation (NRF-2009-0076833).

#### References

- [1] G. Yu, J. Gao, J.C. Hummelen, F. Wudl, A.J. Heeger, Science 270 (1995) 1789.
- [2] S. Gunes, H. Neugebauer, N.S. Sariciftci, Chem. Rev. 107 (2007) 1324.
- [3] B.C. Thompson, J.M.J. Frechet, Angew. Chem. Int. Ed. 47 (2008) 58.
- [4] Y.-J. Chen, S.-H. Yang, C.-S. Hsu, Chem. Rev. 109 (2009) 5868.
- [5] J.W. Chen, Y. Cao, Acc. Chem. Res. 42 (2009) 1709.
- [6] W.L. Ma, C.Y. Yang, X. Gong, K.H. Lee, A.J. Heeger, Adv. Funct. Mater. 15 (2005) 1617.
- [7] G. Li, V. Shrotriya, J.S. Huang, Y. Yao, T. Moriarty, K. Emery, Y. Yang, Nat. Mater. 4 (2005) 864.
- [8] Y. Zhao, Z.Y. Xie, Y. Qu, Y.H. Geng, L.X. Wang, Appl. Phys. Lett. 90 (2007) 043504.
- [9] H.-Y. Chen, J.H. Hou, S.Q. Zhang, Y.Y. Liang, G.W. Yang, Y. Yang, L.P. Yu, Y. Wu, G. Li, Nat. Photon. 3 (2009) 649.
- [10] S.H. Park, A. Roy, S. Beaupré, S. Cho, N. Coates, J.S. Moon, D. Moses, M. Leclerc, K.H. Lee, A.J. Heeger, Nat. Photon. 3 (2009) 297.
- [11] C. Yang, J.Y. Kim, S. Cho, J.K. Lee, A.J. Heeger, F. Wudl, J. Am. Chem. Soc. 130 (2008) 6444.
- [12] G. Zhao, Y. He, Z. Xu, J. Hou, M. Zhang, J. Min, H.-Y. Chen, M. Ye, Z. Hong, Y. Yang, Y. Li, Adv. Funct. Mater. 20 (2010) 1480.
- [13] E.Y. Park, J.S. Park, T.-D. Kim, K.-S. Lee, H.S. Lim, J.S. Lim, C. Lee, Org. Electron. 10 (2009) 1028.
- [14] J.Y. Kim, S.H. Kim, H.-H. Lee, K. Lee, W. Ma, X. Gong, A.J. Heeger, Adv. Mater. 18 (2006) 572.
- [15] M. Chikamatsu, S. Nagamatsu, Y. Yoshida, K. Saito, K. Yase, Appl. Phys. Lett. 87 (2005) 203504.